IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

| Applicants: Young Sun Hwang et al. |) I hereby certify that this paper and the documents referred to as enclosed |
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| Serial No.: To be assigned | therewith are being deposited with the United States Postal Service as first clas |
| Filed: November 21, 2003 (Herewith) | mail, postage prepaid, on November 212003, in an envelope addressed to |
| For: Methods for Forming Fine Photoresist Patterns | Commissioner for Patents, P.O. Box 1450, Alexandria, Virginia 22313-1450 |
| Group Art Unit: To be assigned |) Michael R. Hull |
| Examiner: To be assigned | Reg. No. 35,902 Attorney for Applicant |
| | |
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INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents P.O. Box 1450 Alexandria, Virginia 22313-1450

Sir:

Submitted herewith for consideration by the examiner is a copy of the document identified on the attached Form PTO-1449. Entry and consideration of the submitted document is solicited.

The Commissioner is authorized to charge any fee deficiency required by this paper, or credit any overpayment, to Deposit Account No. 13-2855.

Respectfully submitted,

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November 21, 2003

By:/

Michael R. Hull Reg. No. 35,902

| For m PTO-1449 (Modified) | U.S. Department of Commerce | Atty. Docket No. | Serial No. |
|----------------------------------|-----------------------------|-------------------|----------------|
| | Patent and Trademark Office | 30205/39513 | To be Assigned |
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| INFORMATION DISCLOSURE STATEMENT | | Young Sun Hwang e | t al. |
| | | Filing Date | Group |
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| U.S. PATENT DOCUMENTS | | | | | | | |
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| *Examiner Initials | | Document Number | Issue Date | Name | Class | Subclass . | Filing Date if Appropriate |
| | | 6,541,361 B2 | 04/01/2003 | Ko et al. | | | |

| FOREIGN PATENT DOCUMENTS | | | | | | | |
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| *Examiner Initials | Document Number | Publication Date | Country | Class | Subclass | Translation | |
| | | | | | | Yes | No |
| | 11307437 | 11/05/1999 | Japan | | | Abstract Only | |
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| OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.) | | | | |
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*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.